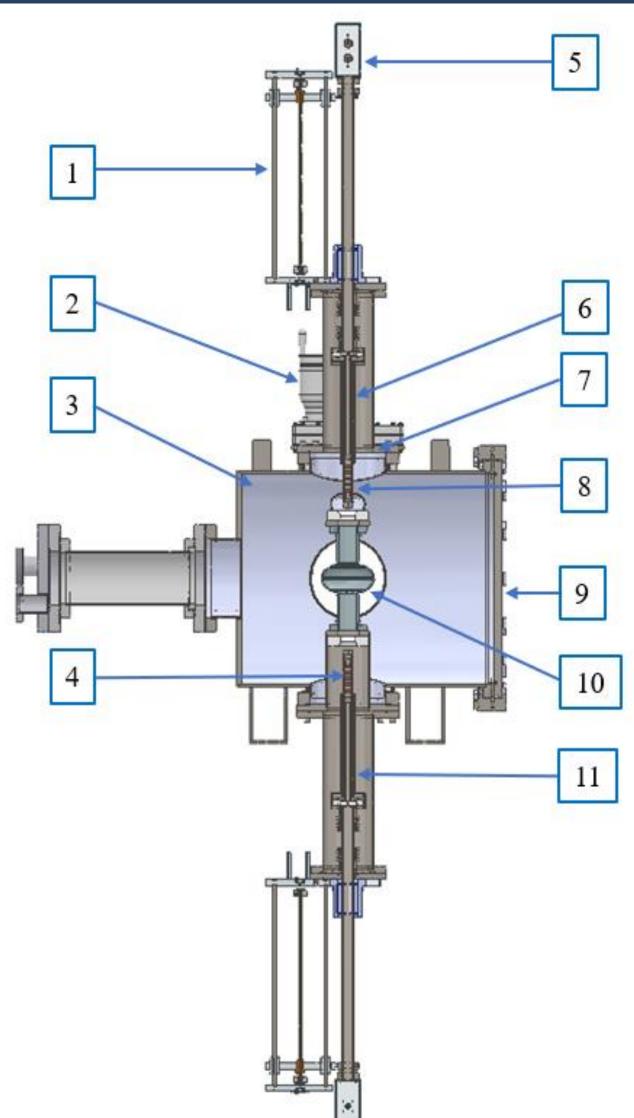


## **USING DC CYLINDRICAL MAGNETRON SPUTTERING SYSTEM** M. S. Shakel, H. E. Elsayed-Ali, Old Dominion University, Norfolk, VA G. Eremeev, Fermi National Accelerator Laboratory, Batavia, IL

# FIRST RESULTS FROM Nb<sub>3</sub>Sn COATINGS OF 2.6 GHz Nb SRF CAVITIES U. Pudasaini, A. M. Valente-Feliciano, Thomas Jefferson National Accelerator Facility, Newport News, VA

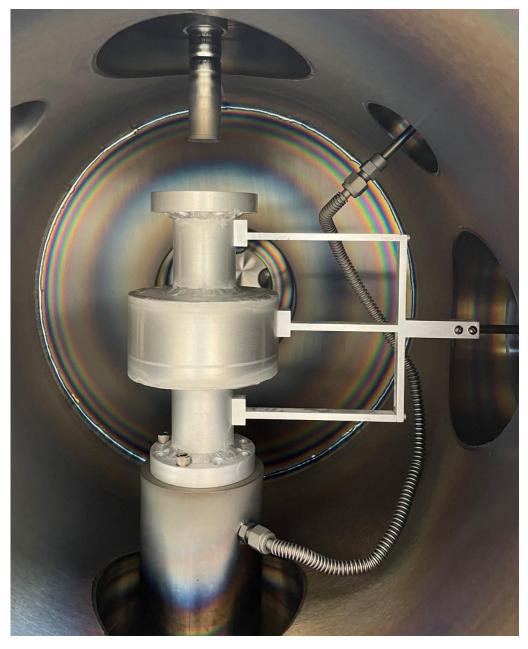
Nb<sub>3</sub>Sn is considered as the next generation material to replace Nb for SRF cavity. A DC cylindrical magnetron sputtering system is designed and commissioned to coat Nb<sub>3</sub>Sn into SRF cavity. A DC cylindrical magnetron sputtering system is designed and commissioned to coat Nb<sub>3</sub>Sn into SRF cavity. cavity, using multilayer sequential sputtering of Nb and Sn followed by annealing at 950 °C for 3 hours, Nb<sub>3</sub>Sn films are fabricated on flat substrates. Later, three 2.6 GHz Nb cavities are coated with ~1 µm Nb<sub>3</sub>Sn film and the coated cavities showed superconducting transition between 17.9 – 18 K. One of the Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at  $E_{acc} = 5$  MV/m. The operation of the cylindrical sputtering system and results from Nb<sub>3</sub>Sn coated cavities demonstrated  $Q_0$  of  $1.1 \times 10^9$  at 2.0 K, both at 2.0 K, b fabrication by cylindrical magnetron sputtering system on flat samples and into Nb cavities are presented.

## **Operation of cylindrical magnetron sputter coater**





Nb discharge at 30 W



Sketch of the cylindrical magnetron sputtering system (1) Magnetron movement controller shaft, (2) Gate valve, (3) Vacuum chamber, (4) Magnets, (5) Water flow controller, (6) Top magnetron, (7) 8" ConFlat port of top magnetron, (8) Tube target, (9) Chamber door, (10) 2.6 GHz Nb SRF cavity, (11) Bottom magnetron. The magnetrons were made by Plasmionique to fit an ODU custom chamber.

#### **Multilayer Sequential Sputtering**

	Total thickness of film (nm)	46 nm Sn
Position		25 nm Sn
		46 nm Sn
Top beam tube	1036	25 nm Sn
Equator	1008	200 nm Nb buffer layer
Bottom beam tube	952	Nb substrate

Multilayers of Nb (~46 nm) and Sn (~25 nm) are sequentially deposited for  $\sim 1 \mu m$  Nb-Sn film on Nb substrates mounted on three positions of the cavity and later annealed at 950 °C for Nb<sub>3</sub>Sn growth.



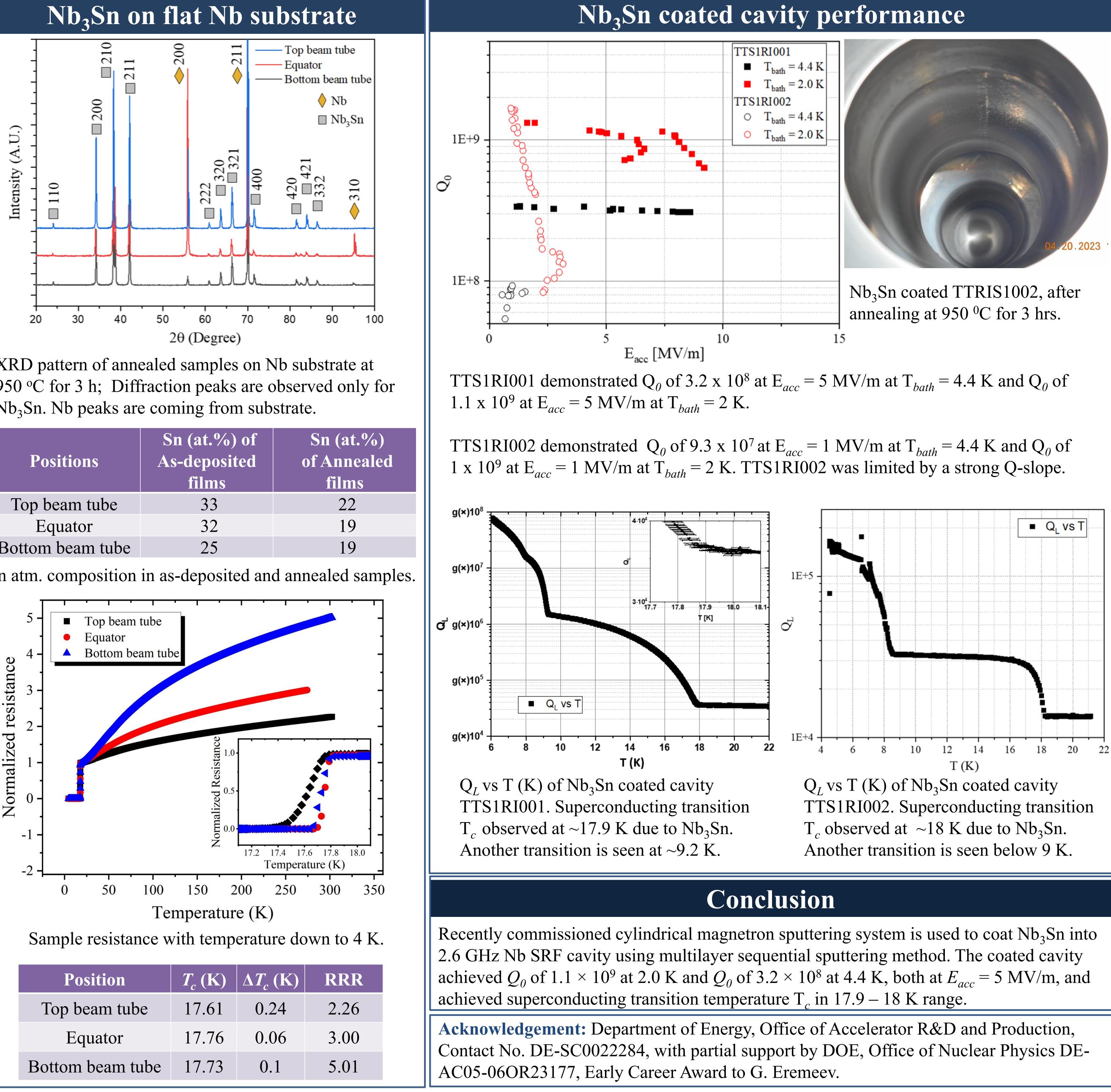
Three 2.6 GHz cavities were coated with  $\sim 1 \ \mu m \ Nb_3Sn$ .

### Abstract

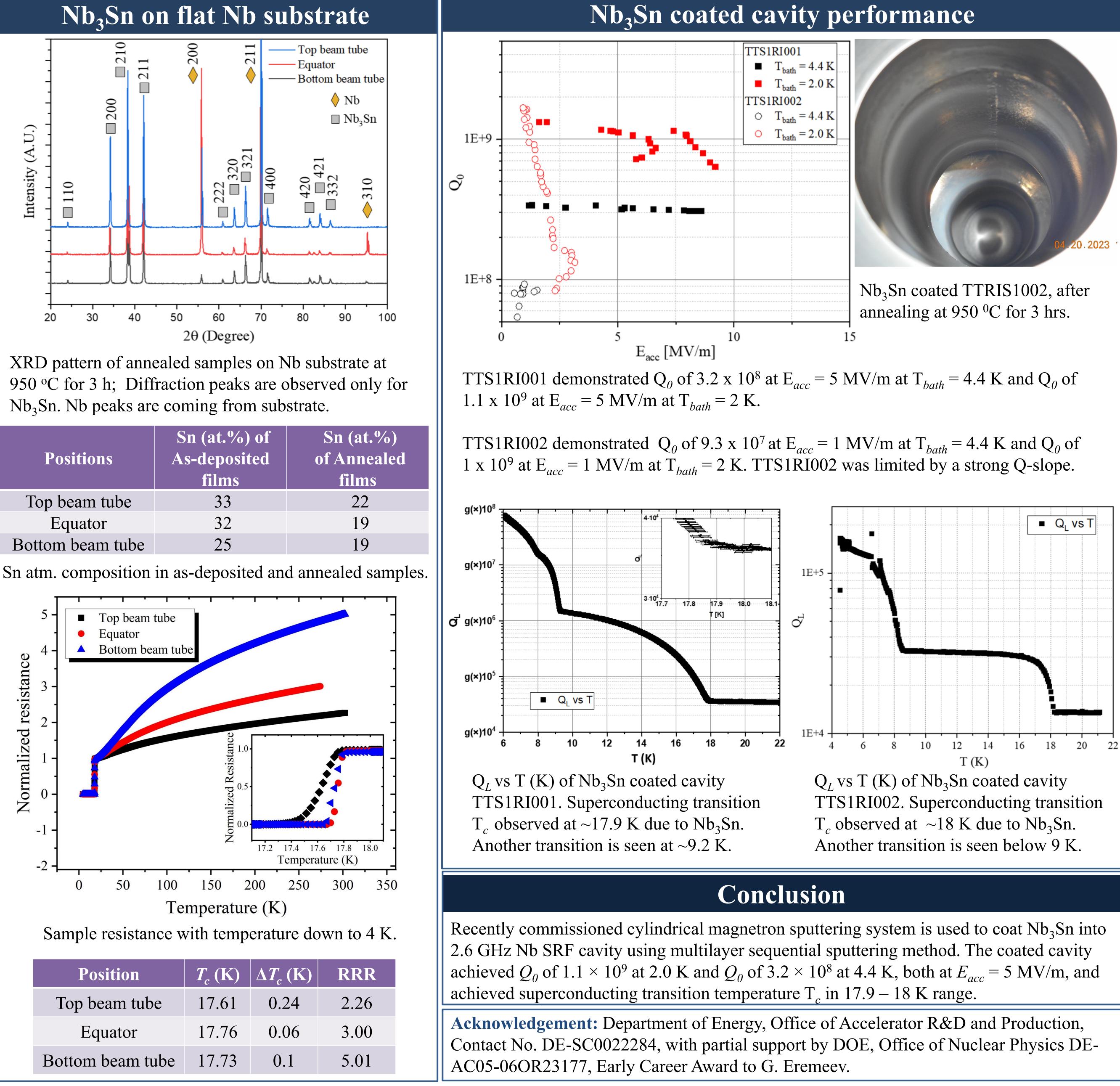
Sn discharge at 8 W

- Nb and Sn discharge conditions are optimized to produce stable and symmetric plasma formation.
- Deposition conditions for Nb<sub>3</sub>Sn fabrication are optimized at 10 mTorr in a mockup cavity replicating 2.6 GHz Nb cavity.

2.6 GHz Nb SRF cavity installed in the system for Nb<sub>3</sub>Sn coating.



Positions	Sn (at.%) of As-deposited films	
Top beam tube	33	
Equator	32	
Bottom beam tube	25	



Position	<i>T<sub>c</sub></i> (K)	$\Delta T_c$ (K)
Top beam tube	17.61	0.24
Equator	17.76	0.06
Bottom beam tube	17.73	0.1

